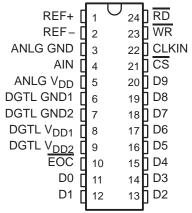
- Power Dissipation . . . 40 mW Max
- Advanced LinEPIC[™] Single-Poly Process Provides Close Capacitor Matching for Better Accuracy
- Fast Parallel Processing for DSP and μP Interface
- Either External or Internal Clock Can Be Used
- Conversion Time . . . 6 μs
- Total Unadjusted Error . . . ±1 LSB Max
- CMOS Technology

description

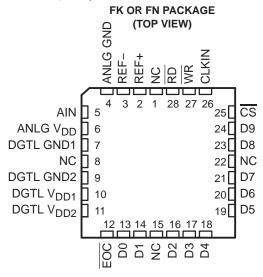
The TLC1550x and TLC1551 are data acquisition analog-to-digital converters (ADCs) using a 10-bit, switched-capacitor, successive-approximation network. A high-speed, 3-state parallel port directly interfaces to a digital signal processor (DSP) or microprocessor (μ P) system data bus. D0 through D9 are the digital output terminals with D0 being the least significant bit (LSB). Separate power terminals for the analog and digital portions minimize noise pickup in the supply leads. Additionally, the digital power is divided into two parts to separate the lower current logic from the higher current bus drivers. An external clock can be applied to CLKIN to override the internal system clock if desired.

The TLC1550I and TLC1551I are characterized for operation from -40° C to 85°C. The TLC1550M is characterized over the full military range of -55° C to 125°C.

J[†] OR DW PACKAGE (TOP VIEW)



† Refer to the mechanical data for the JW package.



NC - No internal connection

AVAILABLE OPTIONS

	PACKAGE								
TA	CERAMIC CHIP CARRIER (FK)	PLASTIC CHIP CARRIER (FN)	CERAMIC DIP (J)	SOIC (DW)					
-40°C to 85°C	_	TLC1550IFN TLC1551IFN	_	TLC1550IDW TLC1551IDW					
-55°C to 125°C	TLC1550MFK	_	TLC1550MJ	_					



This device contains circuits to protect its inputs and outputs against damage due to high static voltages or electrostatic fields. These circuits have been qualified to protect this device against electrostatic discharges (ESD) of up to 2 kV according to MIL-STD-883C, Method 3015; however, it is advised that precautions be taken to avoid application of any voltage higher than maximum-rated voltages to these high-impedance circuits. During storage or handling, the device leads should be shorted together or the device should be placed in conductive foam. In a circuit, unused inputs should always be connected to an appropriated logic voltage level, preferably either V_{CC} or ground.



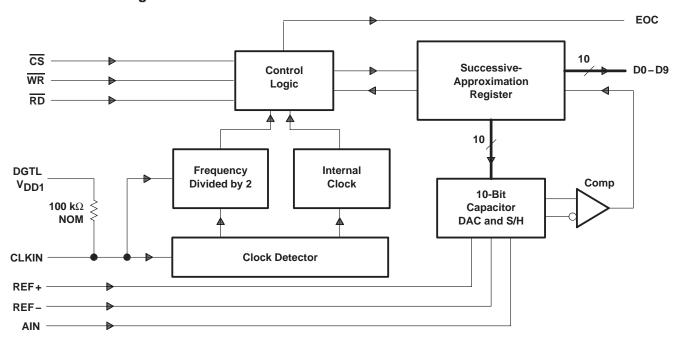
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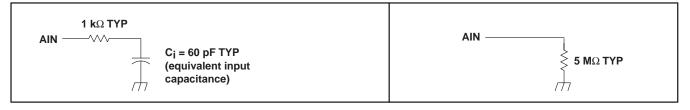
functional block diagram



typical equivalent inputs

INPUT CIRCUIT IMPEDANCE DURING SAMPLING MODE

INPUT CIRCUIT IMPEDANCE DURING HOLD MODE



Terminal Functions

TER	MINAL		
NAME	NO.†	NO.‡	DESCRIPTION
ANLG GND	4	3	Analog ground. The reference point for the voltage applied on terminals ANLG V _{DD} , AIN, REF+, and REF
AIN	5	4	Analog voltage input. The voltage applied to AIN is converted to the equivalent digital output.
ANLG V _{DD}	6	5	Analog positive power supply voltage. The voltage applied to this terminal is designated V _{DD3} .
CLKIN	26	22	Clock input. CLKIN is used for external clocking instead of using the internal system clock. It usually takes a few microseconds before the internal clock is disabled. To use the internal clock, CLKIN should be tied high or left unconnected.
CS	25	21	Chip-select. CS must be low for RD or WR to be recognized by the A/D converter.
D0	13	11	Data bus output. D0 is bit 1 (LSB).
D1	14	12	Data bus output. D1 is bit 2.
D2	16	13	Data bus output. D2 is bit 3.
D3	17	14	Data bus output. D3 is bit 4.
D4	18	15	Data bus output. D4 is bit 5.
D5	19	16	Data bus output. D5 is bit 6.
D6	20	17	Data bus output. D6 is bit 7.
D7	21	18	Data bus output. D7 is bit 8.
D8	23	19	Data bus output. D8 is bit 9.
D9	24	20	Data bus output. D9 is bit 10 (MSB).
DGTL GND1	7	6	Digital ground 1. The ground for power supply DGTL V _{DD1} and is the substrate connection
DGTL GND2	9	7	Digital ground 2. The ground for power supply DGTL V _{DD2}
DGTL V _{DD1}	10	8	Digital positive power-supply voltage 1. DGTL V _{DD1} supplies the logic. The voltage applied to DGTL V _{DD1} is designated V _{DD1} .
DGTL V _{DD2}	11	9	Digital positive power-supply voltage 2. DGTL V _{DD2} supplies only the higher-current output buffers. The voltage applied to DGTL V _{DD2} is designated V _{DD2} .
EOC	12	10	End-of-conversion. \overline{EOC} goes low indicating that conversion is complete and the results have been transferred to the output latch. \overline{EOC} can be connected to the μP - or DSP-interrupt terminal or can be continuously polled.
RD	28	24	Read input. When $\overline{\text{CS}}$ is low and $\overline{\text{RD}}$ is taken low, the data is placed on the data bus from the output latch. The output latch stores the conversion results at the most recent negative edge of $\overline{\text{EOC}}$. The falling edge of $\overline{\text{RD}}$ resets $\overline{\text{EOC}}$ to a high within the $t_{d}(\overline{\text{EOC}})$ specifications.
REF+	2	1	Positive voltage-reference input. Any analog input that is greater than or equal to the voltage on REF+ converts to 1111111111. Analog input voltages between REF+ and REF – convert to the appropriate result in a ratiometric manner.
REF-	3	2	Negative voltage reference input. Any analog input that is less than or equal to the voltage on REF – converts to 0000000000.
WR	27	23	Write input. When $\overline{\text{CS}}$ is low, conversion is started on the rising edge of $\overline{\text{WR}}$. On this rising edge, the ADC holds the analog input until conversion is completed. Before and after the conversion period, which is given by t_{CONV_1} the ADC remains in the sampling mode.



[†] Terminal numbers for FK and FN packages. ‡ Terminal numbers for J, DW, and NW packages.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{DD1} , V _{DD2} , and V _{DD3} (see Note 1)	6.5 V
Input voltage range, V _I (any input)	$-0.3 \text{ V to V}_{DD} + 0.3 \text{ V}$
Output voltage range, V _O	$-0.3 \text{ V to V}_{DD} + 0.3 \text{ V}$
Peak input current (any digital input)	±10 mA
Peak total input current (all inputs)	±30 mA
Operating free-air temperature range, T _A : TLC1550I, TLC1551I	40°C to 85°C
TLC1550M	55°C to 125°C
Storage temperature range, T _{stq}	65°C to 150°C
Case temperature for 10 seconds: FK or FN package	
Lead temperature 1,6 mm (1/16 inch) from the case for 10 seconds: J or NW package	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		MIN	NOM	MAX	UNIT	
Supply voltage, V _{DD1} , V _{DD2} , V _{DD3}		4.75	5	5.5	V	
Positive reference voltage, V _{REF+} (see Note 2)			V _{DD3}		V	
Negative reference voltage, V _{REF} (see Note 2)					V	
Differential reference voltage, V _{REF+} – V _{REF-} (see Note 2)				V _{DD3}	V	
Analog input voltage range					V	
High-level control input voltage, VIH					V	
Low-level control input voltage, V _{IL}			0.8	V		
Input clock frequency, f(CLKIN)				7.8	MHz	
Setup time, CS low before WR or RD goes low, t _{SU(CS)}		0			ns	
Hold time, CS low after WR or RD goes high, th(CS)		0			ns	
WR or RD pulse duration, t _{W(WR)}		50			ns	
Input clock low pulse duration, t _W (L-CLKIN)		40% of period		80% of period		
On another two air to an another T.	TLC155xl	-40		85	°C	
Operating free-air temperature, T _A	TLC1550M	-55		125		

NOTE 2: Analog input voltages greater than that applied to REF+ convert to all 1s (1111111111), while input voltages less than that applied to REF- convert to all 0s (0000000000). The total unadjusted error may increase as this differential voltage falls below 4.75 V.



NOTE 1: V_{DD1} is the voltage measured at DGTL V_{DD1} with respect to DGND1. V_{DD2} is the voltage measured at DGTL V_{DD2} with respect to the DGND2. V_{DD3} is the voltage measured at ANLG V_{DD} with respect to AGND. For these specifications, all ground terminals are tied together (and represent 0 V). When V_{DD1}, V_{DD2}, and V_{DD3} are equal, they are referred to simply as V_{DD}.

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electrical characteristics over recommended operating free-air temperature range, $V_{DD} = V_{REF+} = 4.75 \text{ V}$ to 5.5 V and $V_{REF-} = 0$ (unless otherwise noted)

	PARAMETER		TES1	CONDITIONS	MIN	TYP [†]	MAX	UNIT	
Vон	High-level output voltage		V _{DD} = 4.75 V,	I _{OH} = -360 μA	2.4			V	
V	Lave lavel autout valtage	$V_{DD} = 4.75 \text{ V},$	T _A = 25°C			0.4	.,		
VOL	Low-level output voltage	$I_{OL} = 2.4 \text{ mA}$	$T_A = -55^{\circ}C$ to $125^{\circ}C$			0.5	V		
	0" "		$V_O = V_{DD}$	CS and RD at V _{DD}			10		
loz	Off-state (high-impedance-sta	ate) output current	$V_{O} = 0$,	CS and RD at V _{DD}			-10	μΑ	
lιΗ	High-level input current		$V_I = V_{DD}$			0.005	2.5	μΑ	
Ι _Ι L	Low-level input current (exce	ot CLKIN)	V _I = 0		-2.5	-0.005		μΑ	
Ι _Ι L	Low-level input current (CLKI	N)			-50	-50		μΑ	
	0		V _O = 5 V,	T _A = 25°C	7	14			
los	Short-circuit output current		$V_{O} = 0$,	T _A = 25°C		-12	-6	mA	
I _(DD)	Operating supply current		CS low and RD	high		2	8	mA	
<u> </u>	Innut conscitones	Analog inputs	Coo turnical actu	ivelent inputs TI C4FE0/41		60	90*	~F	
Ci	Input capacitance	Digital inputs	See typical equ	See typical equivalent inputs TLC1550/1I		5	15*	pF	

 $[\]ensuremath{^{\star}}$ On products compliant to MIL-STD-883, Class B, this parameter is not production tested.

[†] All typical values are at $V_{DD} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

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operating characteristics over recommended operating free-air temperature range with internal clock and minimum sampling time of 4 μ s, $V_{DD} = V_{REF+} = 5$ V and $V_{REF-} = 0$ (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	T _A †	MIN	TYP‡	MAX	UNIT	
		TLC1550I		Full range			±0.5		
_	1 Sanada aman	TLC1551I		Full range			±1		
EL	Linearity error	TI 04550M	See Note 3	25°C			±0.5	LSB	
		TLC1550M		Full range			±1		
		TLC1550I		Full range			±0.5		
		TLC1551I		Full range			±1		
EZS	Zero-scale error	TI 0455014	See Notes 2 and 4	25°C			±0.5	LSB	
		TLC1550M		Full range			±1		
		TLC1550I		Full range			±0.5		
_	Full-scale error	TLC1551I	7	Full range			±1	LSB	
EFS		TLC1550M	See Notes 2 and 4	25°C			±0.5		
				Full range			±1		
		TLC1550I		Full range			±0.5		
	Total unadjusted error	TLC1551I	See Note 5	Full range			±1	LSB	
		TLC1550M		25°C			±1		
t _C	Conversion time		fclock(external) = 4.2 MHz or internal clock				6	μs	
ta(D)	Data access time after RD go	es low					35	ns	
t _V (D)	Data valid time after RD goes	high	7		5			ns	
t _{dis(D)}	Disable time, delay time from impedance	RD high to high	See Figure 3				30	ns	
t _d (EOC)	Delay time, RD low to EOC hi	gh			0	15		ns	

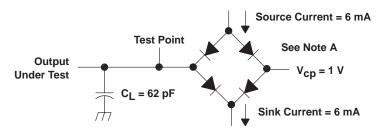
[†] Full range is -40° C to 85° C for the TL155xI devices and -55° C to 125° C for the TLC1550M.

- NOTES: 2. Analog input voltages greater than that applied to REF+ convert to all 1s (1111111111), while input voltages less than that applied to REF convert to all 0s (0000000000). The total unadjusted error may increase as this differential voltage falls below 4.75 V.
 - 3. Linearity error is the difference between the actual analog value at the transition between any two adjacent steps and its ideal value after zero-scale error and full-scale error have been removed.
 - 4. Zero-scale error is the difference between the actual mid-step value and the nominal mid-step value at specified zero scale. Full-scale error is the difference between the actual mid-step value and the nominal mid-step value at specified full scale.
 - 5. Total unadjusted error is the difference between the actual analog value at the transition between any two adjacent steps and its ideal value. It includes contributions from zero-scale error, full-scale error, and linearity error.



[‡] All typical values are at V_{DD} = 5 V, T_A = 25°C.

PARAMETER MEASUREMENT INFORMATION



V_{cp} = voltage commutation point for switching between source and sink currents

NOTE A: Equivalent load circuit of the Teradyne A500 tester for timing parameter measurement

Figure 1. Test Load Circuit

APPLICATION INFORMATION

simplified analog input analysis

Using the circuit in Figure 2, the time required to charge the analog input capacitance from 0 to V_S within 1/2 LSB can be derived as follows:

The capacitance charging voltage is given by

$$V_{C} = V_{S} \left(1 - e^{-t_{C}/R_{t}C_{i}} \right)$$
 (1)

Where:

$$R_t = R_s + r_i$$

The final voltage to 1/2 LSB is given by

$$V_C (1/2 LSB) = V_S - (V_S/1024)$$
 (2)

Equating equation 1 to equation 2 and solving for time t_c gives

$$V_{S} - \left(V_{S}/512\right) = V_{S}\left(1 - e^{-t_{C}/R_{t}C_{i}}\right)$$
(3)

and

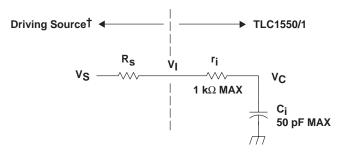
$$t_{C} (1/2 LSB) = R_{t} \times C_{j} \times ln(1024)$$

$$\tag{4}$$

Therefore, with the values given, the time for the analog input signal to settle is

$$t_{\rm C} (1/2 \text{ LSB}) = (R_{\rm S} + 1 \text{ k}\Omega) \times 60 \text{ pF} \times \ln(1024)$$
 (5)

This time must be less than the converter sample time shown in the timing diagrams.



V_I = Input voltage at AIN

V_S = External driving source voltage

R_S = Source resistance

r_i = Input resistance

C_i = Input capacitance

† Driving source requirements:

- Noise and distortion for the source must be equivalent to the resolution of the converter.
- R_S must be real at the input frequency.

Figure 2. Input Circuit Including the Driving Source



PRINCIPLES OF OPERATION

The operating sequence for complete data acquisition is shown in Figure 3. Processors can address the TLC1550 and TLC1551 as an external memory device by simply connecting the address lines to a decoder and the decoder output to \overline{CS} . Like other peripheral devices, the write (\overline{WR}) and read (\overline{RD}) input signals are valid only when \overline{CS} is low. Once \overline{CS} is low, the onboard system clock permits the conversion to begin with a simple write command and the converted data to be presented to the data bus with a simple read command. The device remains in a sampling (track) mode from the rising edge of \overline{EOC} until conversion begins with the rising edge of \overline{WR} , which initiates the hold mode. After the hold mode begins, the clock controls the conversion automatically. When the conversion is complete, the end-of-conversion (\overline{EOC}) signal goes low indicating that the digital data has been transferred to the output latch. Lowering \overline{CS} and \overline{RD} then resets \overline{EOC} and transfers the data to the data bus for the processor read cycle.

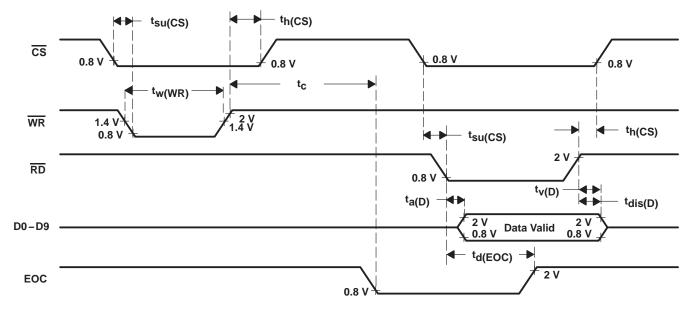


Figure 3. TLC1550 or TLC1551 Operating Sequence



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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
TLC1550IDW	ACTIVE	SOIC	DW	24	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLC1550I	Samples
TLC1550IDWR	ACTIVE	SOIC	DW	24	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLC1550I	Samples
TLC1550IFN	ACTIVE	PLCC	FN	28	37	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLC1550IFN	Samples
TLC1551IDW	ACTIVE	SOIC	DW	24	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLC1551I	Samples
TLC1551IDWR	ACTIVE	SOIC	DW	24	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLC1551I	Samples
TLC1551IFN	ACTIVE	PLCC	FN	28	37	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLC1551IFN	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



PACKAGE OPTION ADDENDUM

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLC1550IDWR	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1
TLC1551IDWR	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLC1550IDWR	SOIC	DW	24	2000	350.0	350.0	43.0
TLC1551IDWR	SOIC	DW	24	2000	350.0	350.0	43.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
TLC1550IDW	DW	SOIC	24	25	506.98	12.7	4826	6.6
TLC1550IFN	FN	PLCC	28	37	497.33	12.95	5080	0
TLC1551IDW	DW	SOIC	24	25	506.98	12.7	4826	6.6
TLC1551IFN	FN	PLCC	28	37	497.33	12.95	5080	0

DW (R-PDSO-G24)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.



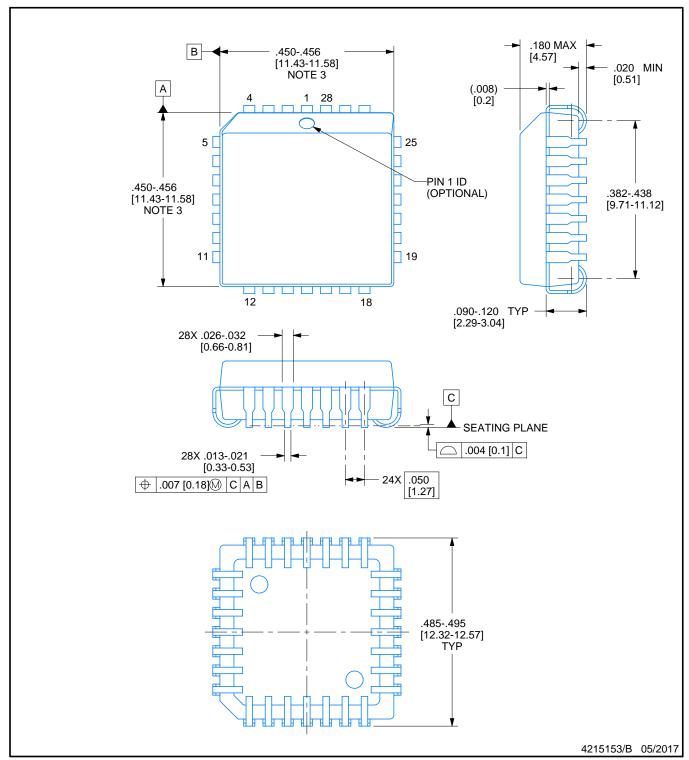


Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4040005-3/C



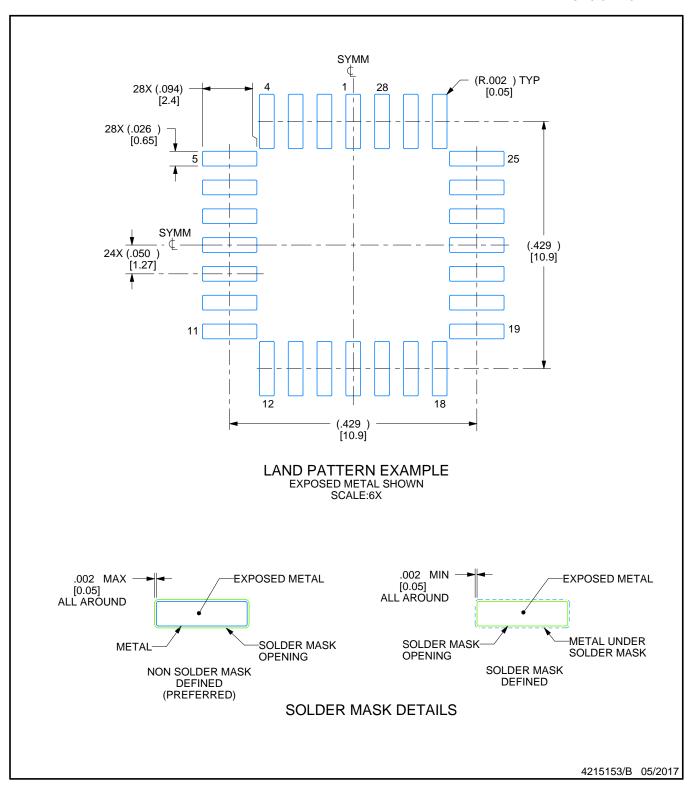




NOTES:

- 1. All linear dimensions are in inches. Any dimensions in brackets are in millimeters. Any dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. Dimension does not include mold protrusion. Maximum allowable mold protrusion .01 in [0.25 mm] per side. 4. Reference JEDEC registration MS-018.



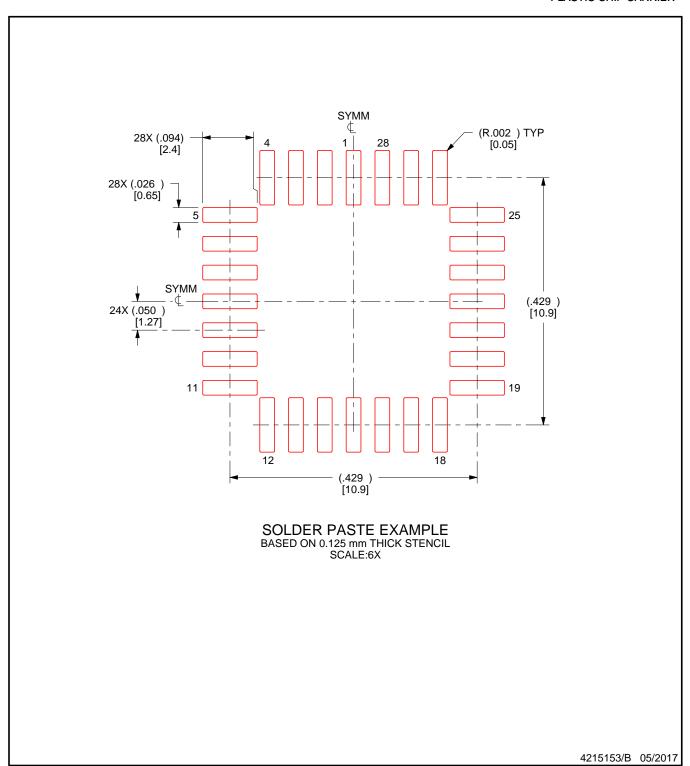


NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



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